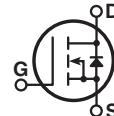
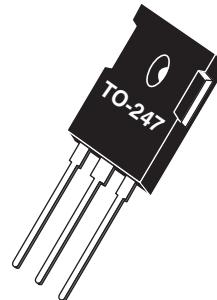


POWER MOS V®

POWER MOS V® is a new generation of high voltage N-Channel enhancement mode power MOSFETs. This new technology minimizes the JFET effect, increase packing density and reduces the on-resistance. Power MOS V® also achieves faster switching speeds through optimized gate layout.

FEATURES

- Faster switching
- Lower Leakage
- 100% Avalanche tested
- Popular TO-247 Package
- RoHS compliant 

APT20M45BVR(G)

Absolute Maximum Ratings

All Ratings: $T_c = 25^\circ\text{C}$ unless otherwise specified.

| Symbol | Parameter | Ratings | Unit |
|----------------|---|------------|---------------------|
| V_{DSS} | Drain Source Voltage | 200 | Volts |
| I_D | Continuous Drain Current @ $T_c = 25^\circ\text{C}$ | 56 | Amps |
| I_{DM} | Pulsed Drain Current ¹ | 224 | |
| V_{GS} | Gate-Source Voltage Continuous | ± 30 | Volts |
| V_{GSM} | Gate-Source Voltage Transient | ± 40 | |
| P_D | Total Power Dissipation @ $T_c = 25^\circ\text{C}$ | 300 | Watts |
| | Linear Derating Factor | 2.4 | W/ $^\circ\text{C}$ |
| T_J, T_{STG} | Operating and Storage Junction Temperature Range | -55 to 150 | $^\circ\text{C}$ |
| T_L | Lead Temperature for Soldering: 0.063" from Case for 10 Seconds | 300 | |
| I_{AR} | Avalanche Current ¹ (Repetitive and Non-Repetitive) | 56 | Amps |
| E_{AR} | Repetitive Avalanche Energy ¹ | 30 | |
| E_{AS} | Single Pulse Avalanche Energy ⁴ | 1300 | mJ |

Static Characteristics
 $T_J = 25^\circ\text{C}$ unless otherwise specified

| Symbol | Parameter | Min | Typ | Max | Unit |
|--------------|---|-----|-----|-----------|---------------|
| BV_{DSS} | Drain-Source Breakdown Voltage ($V_{GS} = 0\text{V}$, $I_D = 250\mu\text{A}$) | 200 | | | Volts |
| $I_{D(on)}$ | On State Drain Current ² ($V_{DS} > I_{D(on)} \times R_{DS(on)}$ Max, $V_{GS} = 10\text{V}$) | 56 | | | Amps |
| $R_{DS(on)}$ | Drain-Source On-State Resistance ² ($V_{GS} = 10\text{V}$, 0.5 $I_{D(Cont.)}$) | | | 0.045 | Ohms |
| I_{DSS} | Zero Gate Voltage Drain Current ($V_{DS} = V_{DSS}$, $V_{GS} = 0\text{V}$) | | | 25 | μA |
| | Zero Gate Voltage Collector Current ($V_{GS} = 0.8 V_{DSS}$, $V_{DS} = 0\text{V}$, $T_c = 125^\circ\text{C}$) | | | 250 | |
| I_{GSS} | Gate-Source Leakage Current ($V_{GS} = \pm 30\text{V}$, $V_{DS} = 0\text{V}$) | | | ± 100 | nA |
| $V_{GS(th)}$ | Gate Threshold Voltage ($V_{DS} = V_{GS}$, $I_D = 1.0\text{mA}$) | 2 | | 4 | Volts |

 **CAUTION:** These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

Dynamic Characteristics

APT20M45BVR(G)

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Unit |
|--------------|--------------------------------|---|-----|------|------|------|
| C_{iss} | Input Capacitance | $V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1MHz$ | | 4050 | 4860 | pF |
| C_{oss} | Output Capacitance | | | 980 | 1375 | |
| C_{rss} | Reverse Transfer Capacitance | | | 300 | 450 | |
| Q_g | Total Gate Charge ¹ | $V_{GS} = 10V$ $V_{DD} = 0.5V_{DSS}$ $I_D = I_{D[cont]} @ 25^\circ C$ | | 130 | 195 | nC |
| Q_{ge} | Gate-Source Charge | | | 30 | 45 | |
| Q_{gd} | Gate- Drain ("Miller") Charge | | | 55 | 80 | |
| $t_{d(on)}$ | Turn-on Delay Time | $V_{GS} = 10V$ $V_{DD} = 0.5V_{DSS}$ $I_D = I_{D[cont]} @ 25^\circ C$ | | 12 | 24 | ns |
| t_r | Rise Time | | | 14 | 28 | |
| $t_{d(off)}$ | Turn-off Delay Time | | | 43 | 70 | |
| t_f | Fall Time | $R_G = 1.6\Omega$ | | 7 | 14 | |

Source-Drain Diode Ratings and Characteristics

| Symbol | Characteristic / Test Conditions | Min | Typ | Max | Unit |
|----------|--|-----|-----|-----|---------|
| I_s | Continuous Source Current (Body Diode) | | | 56 | Amps |
| I_{SM} | Pulse Source Current ¹ (Body Diode) | | | 224 | |
| V_{SD} | Diode Forward Voltage ² ($V_{GS} = 0V$, $I_s = -I_{D[Cont.]}$) | | | 1.3 | Volts |
| t_{rr} | Reverse Recovery Time ($I_s = -I_{D[Cont.]}$, $dI_s/dt = 100A/\mu s$) | | 280 | | nS |
| Q_{rr} | Reverse Recovery Time ($I_s = -I_{D[Cont.]}$, $dI_s/dt = 100A/\mu s$) | | 3.5 | | μC |

Thermal Characteristics

| Symbol | Characteristic | Min | Typ | Max | Unit |
|-----------------|---------------------|-----|-----|------|-------------|
| $R_{\theta JC}$ | Junction to Case | | | 0.42 | C°/W |
| $R_{\theta JA}$ | Junction to Ambient | | | 40 | |

① Repetitive Rating: Pulse width limited by maximum junction temperature.

③ See MIL-STD-750 Method 3471

② Pulse Test: Pulse width < 380 μs , Duty Cycle < 2%

④ Starting $T_j = +25^\circ C$, $L = 830\mu H$, $R_G = 25\Omega$, Peak $I_L = 56A$

Microsemi Reserves the right to change, without notice, the specifications and information contained herein.

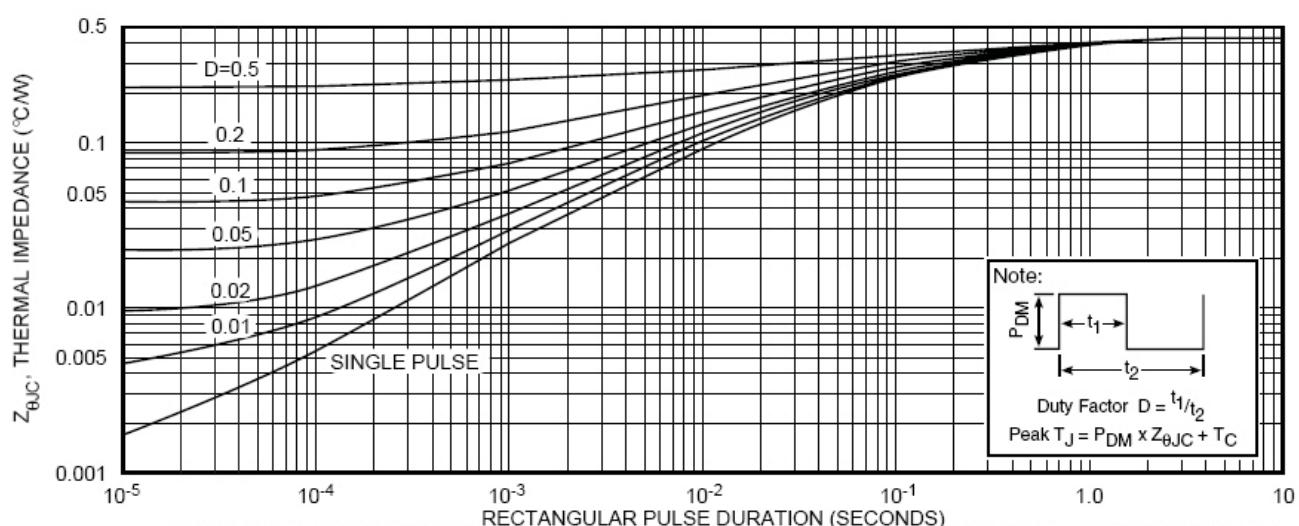


FIGURE 1. MAXIMUM EFFECTIVE TRANSIENT THERMAL IMPEDANCE, JUNCTION-TO-CASE vs PULSE DURATION

Typical Performance Curves

APT20M45BVR(G)

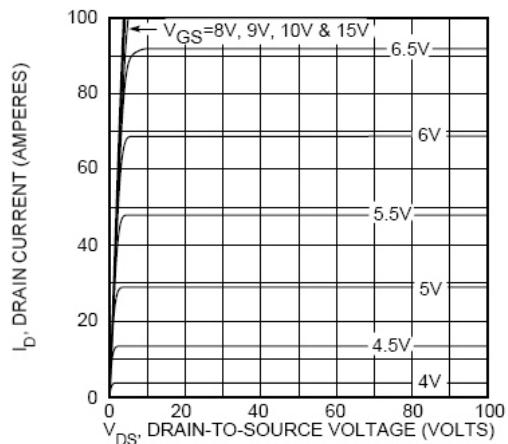


FIGURE 2, TYPICAL OUTPUT CHARACTERISTICS

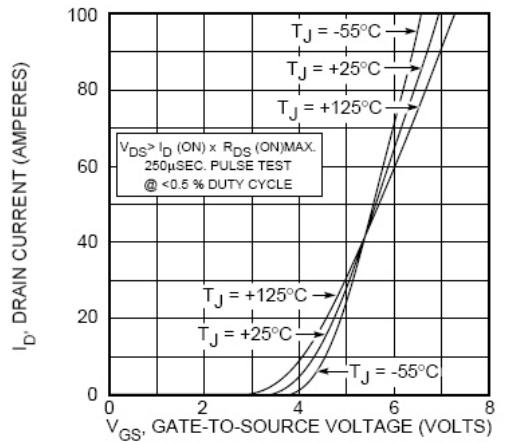


FIGURE 4, TYPICAL TRANSFER CHARACTERISTICS

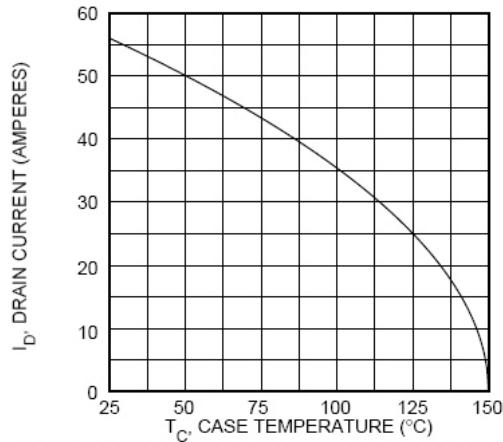


FIGURE 6, MAXIMUM DRAIN CURRENT vs CASE TEMPERATURE

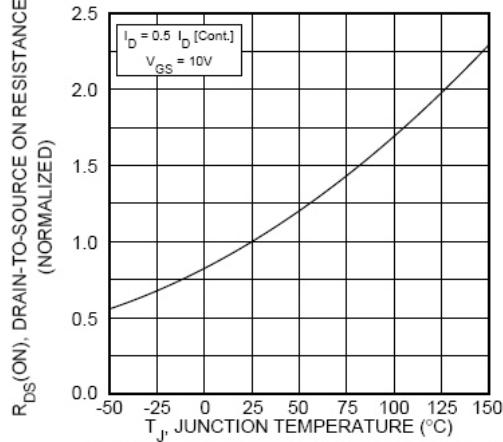


FIGURE 8, ON-RESISTANCE vs. TEMPERATURE

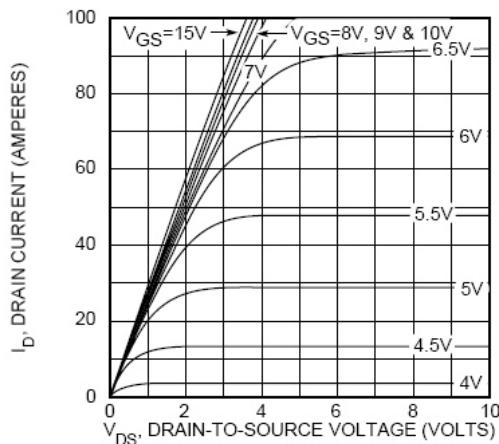


FIGURE 3, TYPICAL OUTPUT CHARACTERISTICS

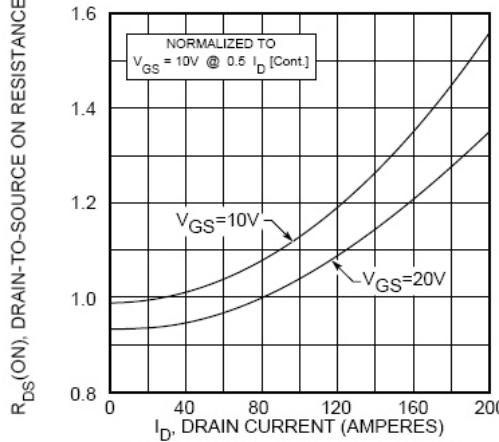


FIGURE 5, $R_{DS(\text{ON})}$ vs DRAIN CURRENT

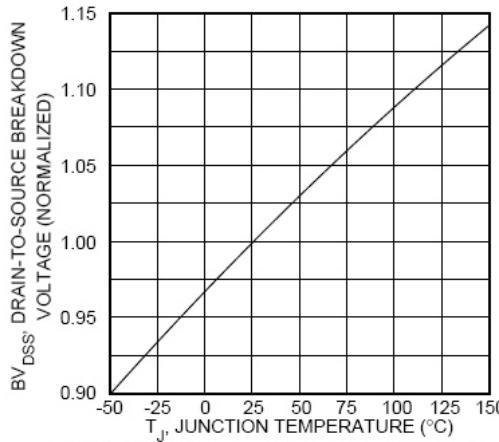


FIGURE 7, BREAKDOWN VOLTAGE vs TEMPERATURE

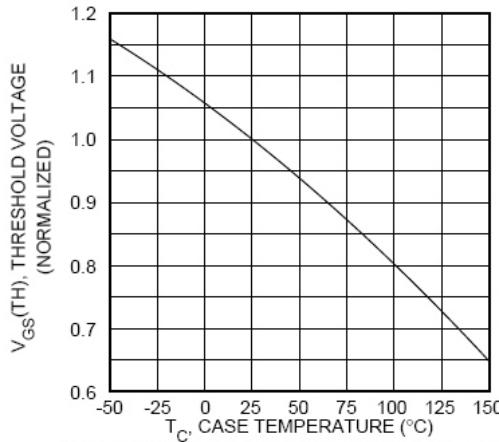


FIGURE 9, THRESHOLD VOLTAGE vs TEMPERATURE

Typical Performance Curves

APT20M45BVR(G)

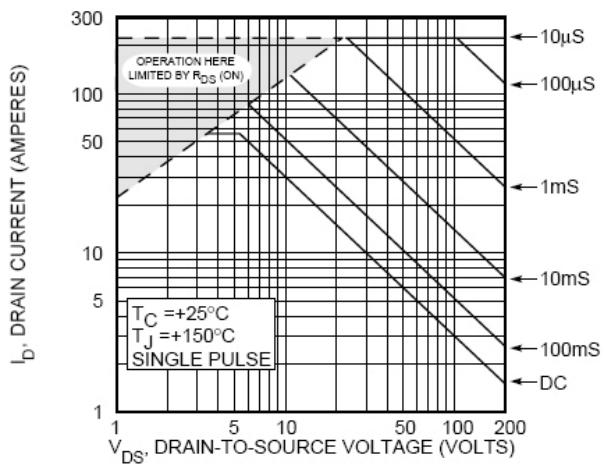


FIGURE 10, MAXIMUM SAFE OPERATING AREA

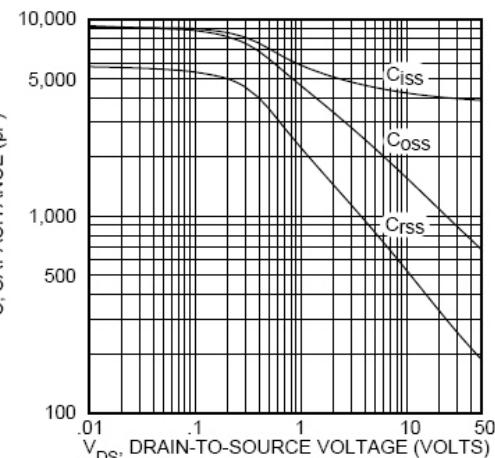


FIGURE 11, TYPICAL CAPACITANCE vs DRAIN-TO-SOURCE VOLTAGE

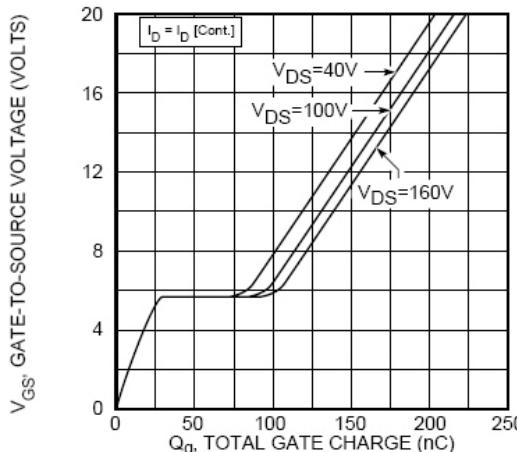


FIGURE 12, GATE CHARGES vs GATE-TO-SOURCE VOLTAGE

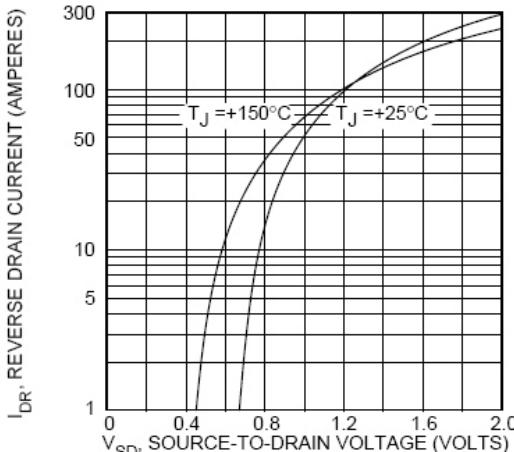
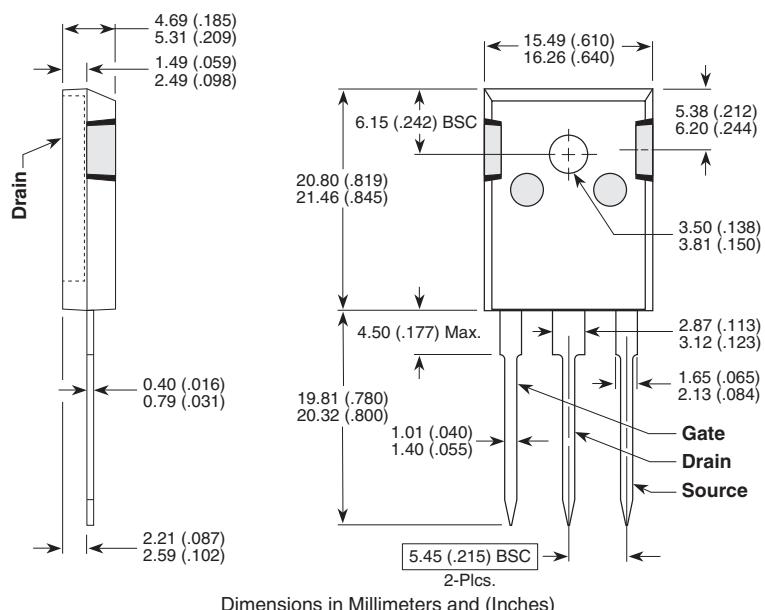


FIGURE 13, TYPICAL SOURCE-DRIVE DIODE FORWARD VOLTAGE

TO-247 (B) Package Outline

e3 100% Sn Plated



Microsemi's products are covered by one or more of U.S. patents 4,895,810 5,045,903 5,089,434 5,182,234 5,019,522 5,262,336 6,503,786 5,256,583 4,748,103 5,283,202 5,231,474 5,434,095 5,528,058 6,939,743, 7,352,045 5,283,201 5,801,417 5,648,283 7,196,634 6,664,594 7,157,886 6,939,743 7,342,262 and foreign patents. US and Foreign patents pending. All Rights Reserved.